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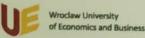


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The Development of Physically Correct Reflectance Model Based on Logarithm Function

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Abstract-The purpose of this work is to develop the absically correct reflectance model based on logarithm and inction, which allows to increase the realism level of objects visualization.

model, bidirectional Keywords-reflectance logarithm function, physically correct model, symbolic regression, mergy conservation law, normalizing coefficient.

INTRODUCTION

The main requirements to objects visualization [1] are the high speed and enough level of realism. The high speed of objects visualization is provided through using effective surface shading methods [2] and simple forms of light reflectance models. In order to achieve high realism level of objects visualization the surface microfacet division [3] and wave-particle dual theory can be used depending on the task. Realistic light reflectance models [4] should comply with the mergy conservation law and Helmholtz reciprocity principle. The Helmholtz reciprocity principle [5] lies in the possibility of swapping the income and outcome light direction. The energy conservation law [6] means that the amount of light scattered over the surface can't be bigger than the amount of incident at surface light.

The reflectance models that comply with the energy conservation law are called physically correct [7]. Therefore, the development of new physically correct light reflectance models is necessary.

LITERATURE ANALYSIS

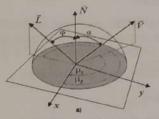
The two main approaches to scene rendering are resterization and ray tracing.

The essence of ray tracing method [8] is that the light ray directed from the camera through the image pixel, the pixel tolor intensity is calculated when the ray intersects with the scale point. This method is used only for the tasks of highly tellistic graphics. The method is very laborious so it's not graphics. The method is very used for the tasks of dynamic graphics.

The rasterization method is more productive and lies in rasterization method is more productive and into twoinchain the three-dimensional scene model into account. and the visibility of points is taken into account.

The optical characteristics of surface during the shading

are described by bidirectional reflectance distribution functions [8] (BRDF). BRDF [9] show the ratio of reflected light radiance in the direction V to irradiance in incident light direction \bar{L} (Fig. 1).



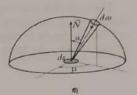


Fig. 1. The data for BRDF calculation

Bidirectional reflectance distribution functions are calculated using the formula [6]

$$\frac{\mathrm{d}I(\vec{V_i})}{I(L_i)\cos\alpha_i\,\mathrm{d}\omega_i}$$

where $d\omega$ - differential solid angle, $I(\vec{V}_i)$ i $I(L_i)$ - light intensity in the reflected light direction and incident light direction respectively.

The light intensity in given direction is calculated using

$$I = \frac{\mathrm{d}\Phi}{\mathrm{d}s\cos(\alpha)\,\mathrm{d}\omega}$$

where ds - area of light incidence, Φ - the radiant flux

The main two types [10] of BRDFs are theoretical value. (physically accurate) and empirical.

The theoretical BRDFs are used for modelling the surface light reflection with exact consideration of physical laws. BRDFs of this type are computationally expensive, so they are rarely used in highly productive computer graphics are rarely used in the surface reflectance models the surface systems. In the theoretical reflectance models the surface systems. In the throad using a big number of microfacets, roughness is described using a big number of microfacets. roughness is described and Cook-Torrance BRDFs.
Among such models the Ward and Cook-Torrance BRDFs.

Ward BRDF is based on using the mean facet orientation deviation m. For the BRDF calculation the formula is used [10]

$$\frac{1}{\sqrt{(\vec{N}\cdot\vec{L})(\vec{N}\cdot\vec{V})}}\frac{1}{4\pi m^2}e^{\frac{(\vec{N}\cdot\vec{H})^2-1}{m^2(\vec{N}\cdot\vec{H})^2}},$$

where \vec{N} – vector normal, \vec{H} – half-vector between \vec{L} and \vec{V} .

For the Cook-Torrance BRDF [10] calculation the Beckmann microfacet distribution D, Fresnel factor F (describes the reflection from the microfacet), the geometrical attenuation factor G (describes the shadowing of facets) are used. The function is calculated using the formula

$$\frac{D \cdot F \cdot G}{\pi(\vec{N} \cdot \vec{L})(\vec{N} \cdot \vec{V})}.$$

The empirical BRDFs approximately represent the surface reflectance characteristics, therefore they are characterized by high productivity.

The most common empirical BRDFs are Phong and Blinn functions [11], considering the simplicity of their calculation and decent results of objects visualization. Phong BRDF is calculated using the formula [12]

$$\cos(x)^n$$
,

where n is surface specularity coefficient (shows the surface reflection degree), x – the angle between light reflection vector to viewer \vec{V} and specular light reflection vector \vec{R} .

Energetically correct Phong model [6] includes normalizing coefficient calculation using formula

$$(n+1)/2\pi$$
.

Blinn BRDF [13] modifies the Phong BRDF using the angle between normal and vector $\vec{H} = (\vec{L} + \vec{V}) / |\vec{L} + \vec{V}|$. This angle [13] shows the value of surface deviation from maximum specular direction.

When the surface specularity coefficient reaches big values, the calculation complexity of Blinn and Phong functions is starting exponentially increasing.

Schlick BRDF [14] is the first degree approximation of the Blinn-Phong BRDF. Schlick BRDF is calculated using the formula

$$\frac{\cos(x)}{n-n\cdot\cos(x)+\cos(x)}.$$

The disadvantage of function is not enough level of glow's attenuation zone reproduction realism.

The modified Schlick BRDF, which was developed article authors, is calculated using the formula [15]

$$\frac{2\cos(x)}{(1.25)(n-n\cdot\cos(x)+1.25\cos(x))^2}.$$

The modified Schlick function is more accurate in the attenuation zone of glare.

Gauss BRDF [10] is a function based on angle calculation between vectors. This BRDF provides the accurate glave reproduction but the angle calculation is a computationally complex operation. The function is calculated using the

$$e^{-\frac{n\cdot(\angle(\vec{H},\vec{L}))^2}{2}}$$

The logarithm function based Blinn-Phong BRDF approximation is characterized with low computational requirements and high precision glow's epicenter and attenuation zones reproduction. The function is calculated using the formula [10]

$$(1-0.5 \cdot \log_2(1-n \cdot \log_2(\cos(x))))$$

Let's mark logarithm function based BRDF as F_{let} . Blinn-Phong BRDF as F_B , Schlick BRDF as F_L .

Fig. 2 shows the plots of F_{log} , F_B , F_s when n=20.

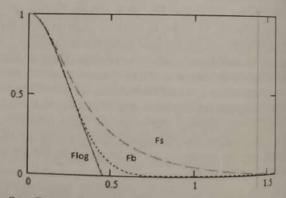


Fig. 2. F_{log} , F_B , F_s plots when n = 20

Fig. 3 shows the plots of maximum relative errors δ between F_{log} , F_s and F_B at the interval $n \in [1;1000]$ in the glow's epicenter zone.

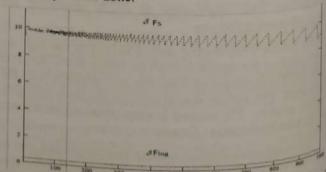
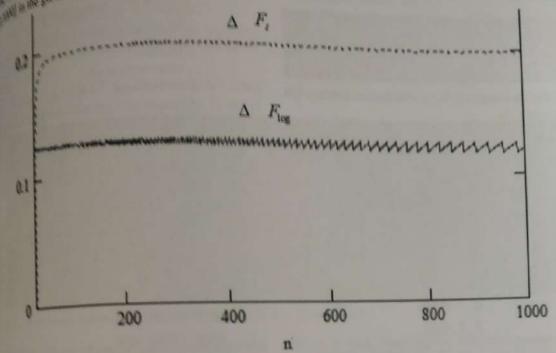


Fig. 3. The plots of maximum δ between F_{log} , F_s and F_B , at the interval $n \in [1;1000]$ in the glow's epicenter zone

and F_a at the interval $\frac{1}{2}$ and $\frac{1}{2}$ at the interval $\frac{1}{2}$ and $\frac{1}$

Fig. 4 shows the plots of maximum absolute errors Δ between F_{\log} , F_{i} and F_{ii} at the interval $n \in [1;1000]$.



is Depice of maximum. A between F_{\log} , F_s and F_g at the interval $n \in [1;1000]$

The maximum Δ between F_{hg} and F_B at the interval [0.1] is 0.12, the maximum Δ between F_s and F_B is [0.1]

Therefore, F_{aa} in comparison with F_{s} provides more made F_{s} approximation in glow's epicenter and making zones.

The disadvantage of F_{log} is non-compliance with the conservation law. So the calculation of F_{log} conservation is needed.

NORMALIZING COEFFICIENT SEARCH FOR THE LOGARITHM FUNCTION BASED REFLECTANCE MODEL

The surface light reflectance model should comply with the conservation law. This is expressed mathematically condition [15]

$$\int_{\Omega} f_{r}(\omega, \omega_{s}) \cdot \cos(\theta) d\omega \leq 1,$$

where $d\omega = \sin(\theta) d\theta d\phi$, $f_r(\omega, \omega_r)$ — bidirectional distribution function.

We enter the normalizing coefficient coef(n) for F_{log} in the condition of energy maximization we obtain the

$$^{\operatorname{coef}(n)\!\!\int\limits_{\Omega}\!\!f_{\tau}(\omega,\omega_{\tau})\cdot\operatorname{cos}(\theta)\,\mathrm{d}\,\omega=1,$$

where coef(n) is normalizing coefficient.

The $f_r(\omega, \omega_r)$ is replaced by F_{log} formula. We move to spherical coordinates. The equation takes the form

$$coef(n) \int_{0}^{2\pi} \int_{0}^{gram(n)} (1 - 0.5 \cdot \log_{2}(1 - n * \log_{2}(\cos(\theta)))) \cdot cos(\theta) \sin(\theta) d\theta d\phi = 1.$$

The limit value of F_{\log} argument $\operatorname{gran}(n)$, at which the function reaches zero, is calculated using the formula

$$\operatorname{gran}(n) = \operatorname{acos}(e^{\frac{-2.08}{n}}).$$

After the integration of left part by $\,d\phi\,$ the equation takes the form

$$\operatorname{coef}(n) \cdot 2\pi \cdot \int_{0}^{\operatorname{gran}(n)} (1 - 0.5 \cdot \log_{2}(1 - n * \log_{2}(\cos(\theta)))) \cdot \\ \cdot \cos(\theta) \sin(\theta) d\theta = 1.$$

The integral expression is replaced by the Int(n)

$$\operatorname{Int}(n) = \int_{0}^{\operatorname{gnos}(n)} (1 - 0.5 \cdot \log_{1}(1 - n \cdot \log_{2}(\cos(\theta)))) \cos(\theta) \sin(\theta) d\theta.$$

Then the normalizing coefficient coef(n) is calculated using formula

$$\operatorname{coef}(n) = \frac{1}{2\pi \cdot \operatorname{Int}(n)} .$$

The values of coef(n) were calculated depending on $n \in [1,1000]$. The sample of 50 n, coef(n) pairs was saved in the text file (Fig. 5).

100
n, coef(
1,0.483
2,0.665
3,0.855
4,1.048
5,1.243
6,1.438
7,1.634

Fig. 5. The saved in the text file sample of n, coef(n) pairs

The data of text file were used for the coef(n) formula selection using the software tool TuringBot (Fig. 6).

Input		Advanced
Input file	■ знач.txt	12
Target variable	у	
Input variables	n Row number	
All/none		

Fig. 6. Making the choice of text file for coef(n) formula selection in TuringBot

The root mean square error (RMS) was chosen as the error metric. Among the possible operations of formula the addition, multiplication and division were chosen (Fig. 7).

Search options				
Search metric	RMS error			
Train/test split	No cross-validation			
Test sample	Chosen randomly			
Constants				
Integer constar	eger constants only			
Basic functions				
Addition	m			
Multiplication Division	200			

Fig. 7. The setting of error metric and possible formula opening

The set of possible coef(n) formulas was reconstructed (Fig. 8). The second last formula was chosen from the taking to account its simplicity and low error value.

1 62,583411 58.7142 3 0.183519 0.197639*n 5 0.006839 0.197244*(n+1.27235) 9 0.006503 (0.197234-(-1.39266e-08*n))*(n+1.2752) 10 0.001128 0.197253*((0.224161/n)+1.2449+n) 12 0.000200 0.197254*(n+1.22391)*(n.6318389/n.1641672*n)		Size	Error	Function
5 0.006839 0.197244*(n+1.27235) 9 0.006503 (0.197234-(-1.39266e-08*n))*(n+1.2752) 10 0.001128 0.197253*((0.224161/n)+1.2449+n)		1	62,583411	58.7142
9 0,006503 (0.197234-(-1.39266e-08*n))*(n+1.2752) 10 0.001128 0.197253*((0.224161/n)+1.2449+n)		3	0.183519	0.197639*n
10 0.001128 0.197253*((0.224161/n)+1.2449+n)		5	0,006839	0.197244*(n+1.27235)
313123 ((022413 ()1) 1243 11)		9	0,006503	(0.197234-(-1.39266e-08*n))*(n+1.2752)
12 0.000280 0.1972541/n+1.2389.h+ln.0681339/ln.641677-nn		10	0,001128	0.197253*((0.224161/n)+1.2449+n)
Brown Commission Sections of the Comment of the Com		12	0.000280	0.197254*(n+1.23891)+(0.0681339/(0.641677+n))
18 0,000273 0.197254*(n-{0.242046/ (-0.680778+(-0.00838297*n))*n-0.475525)		18	0,000273	0.197254*(n-{0.242046/((-0.680778+(-0.00838297*n))*n-0.475325)+13/11

Fig. 8. Set of possible coef(n) formulas in TuringBot

So, coef(n) for F_{log} is calculated using the formula

$$0.197(n+1.24) + \frac{0.068}{0.64+n}$$

Fig. 9 shows the plot of absolute errors Δ between expression $\operatorname{coef}(n) \cdot 2\pi \cdot \operatorname{Int}(n)$ and 1 depending $n \in [1,1000]$.

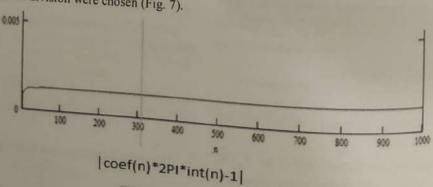


Fig. 9. A depending on $n \in [1,1000]$

by maximum Δ value at the interval $n \in [1,1000]$ is

PRACTICAL USE OF THE RESULTS

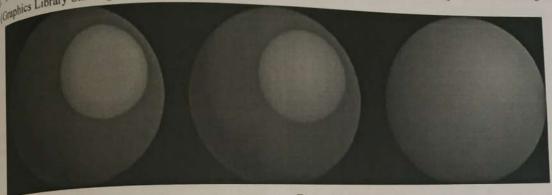
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No visualization of use of the modified logarithm
No visualization of use of the modified logarithm he visualization of the modified logarithm based reflectance model the web tool OneShader

the code of F_{log} implementation using this Library Shading Language). Fig. 1.1 Promentation using Language). Fig. 11 shows

the visualized spheres using the energetically correct logarithm function based model, original logarithm function based model, Schlick model.

float speclog=min(max((0.197*(n+1.24)+0.068)

Fig. 10. Code of energetically correct $F_{\rm log}$ implementation using GLSL



 $_{\rm int}$ Created spheres images based on energetically correct $F_{\rm log}$, original $F_{\rm log}$, $F_{\rm g}$ respectively

Summarizing, the use of energetically correct logarithm faction based model allows more precise glow's epicenter attenuation zones reproduction in comparison with Fnd original F

V. CONCLUSIONS

in the article the energetically correct surface reflectance model based on logarithm function was developed. The burthm function based model compared to the Schlick notel allows approximating the reference Blinn-Phong nodel with considerably smaller absolute and relative errors.

The original logarithm function based reflectance model as modified by introducing the normalizing coefficient. The aculated with the usage of symbolic regression normalizing aefficient formula provides compliance with the energy unservation law and energy maximization condition.

Using GLSL shading language the visualization realism he was compared for the Schlick model, the original and regetically correct models based on logarithm function. It so found that the proposed model among the considered provides the most accurate specular color component

The developed surface reflectance model can be used for he tasks of highly realistic computer graphics.

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